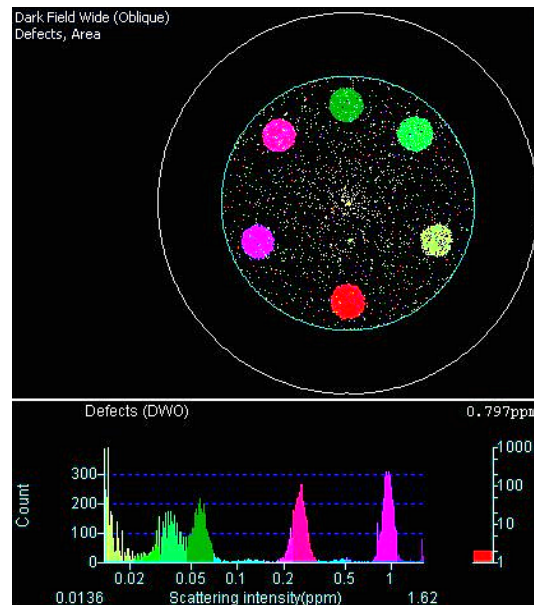


Calibration Curves for KLA-Tencor Tools

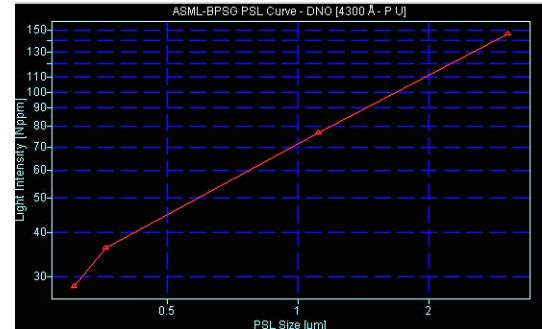
KEEP PARTICLE COUNTS AHEAD OF THE CURVE. Properly generated calibration curves ensure the best matched metrology between different films over multiple generations of tools. They are an essential element used in support of ISO 9000 and TS 16949 quality programs at customer sites worldwide.

Pictured on the left is the map of a wafer with an oxide film grown on it, which was deposited with PSL spheres of various sizes. On the right is the calibration curve derived from it.



PRODUCT DESCRIPTION

Calibration Curves for KLA-Tencor SPX and Surfscan 62XX instruments are calculated from the deposition of polystyrene latex spheres (PSL) to customer supplied silicon wafers of known film types. The Calibration Curve (also known as a light calibration table) correlates the measured intensity of scattered light to the known diameters of various PSL spheres. Once measured, VLSI Standards constructs a light calibration table which is shipped to the customer either on CD or via e-mail. The wafers deposited with PSL are returned back to the customer at no extra charge. Owning the wafers enables customers to periodically recalibrate and optimize in the field.



PRODUCT SPECIFICATIONS

- **Tools Supported by VLSI Standard's**
Surfscan 6200, Surfscan 6220, SP-1, SP-1 TBI, SP-1 DLS, SP-2, SP-2 XP
- **Wafer diameters supported:**
200 mm and 300 mm

PLEASE NOTE: VLSI Standards cannot accept any films or film stacks that contain gold, cobalt or any other materials known to be contaminative to standard silicon processing and cleanroom environments. We do, however, accept Copper and films used in Copper processing, as we maintain separate facilities for Cu and for non-Cu materials.*

* Sizes in other ranges may be available. Please check with VLSI Standards.